

On the Kinetic Roughening in Polymer Film Growth by Vapor Deposition

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In an interesting recent Letter [1], Zhao et al. report on an experimental investigation of kinetically rough polymeric (p-xylene) thin film growth using atomic force microscopy. The main experimental finding [1] is a measurement of the effective critical exponents β (growth exponent), α (roughness exponent), z (dynamical exponent), and λ (slope exponent) characterizing kinetically rough surface growth in p-xylene. These exponents are obtained [1] from a statistical study of the height-height correlation function of the evolving growth front as a function of growth time (or, equivalently, the average film thickness). The standard dynamic scaling ansatz for kinetic surface roughening asserts that the root mean square surface width $W(t)$, the surface correlation length $\xi(t)$, and the average mound slope [2] $M(t)$ scale as $W(t) \sim t^\beta$; $\xi(t) \sim t^{1/z}$; $M(t) \sim t^\lambda$ in the pre-stationary growth regime characterized by $t \ll L^z$ (or equivalently $\xi \ll L$) with the dynamical exponent z given by $z = \alpha/\beta$. (An equivalent description follows from the height correlation function used in Ref. [1].) In Ref. [1] the measured exponent values are reported as $\beta = 0.25 \pm 0.03$; $\alpha = 0.72 \pm 0.05$; $1/z = 0.31 \pm 0.02$; $\lambda = 0.1 - 0.3$. Although the exponents α , β , and z reported in Ref. [1] are completely consistent with the theoretical predictions [3] of Lai and Das Sarma (LD) for the conserved nonlinear MBE growth universality class, as was noted in Ref. [1], the authors of Ref. [1] claim that their observations indicate a novel universality class hitherto unknown in the literature. The basis for this claim is the measured non-zero value of the slope exponent λ ($\approx 0.1 - 0.3$), whereas the LD theory [3], according to Ref. [1], “predicts stationary growth with a constant local slope” leading to $\lambda = 0$.

In this Comment we point out that *all* the experimentally measured exponents (α , β , z , λ) in Ref. [1] are *completely consistent with those of the discrete Das Sarma-Tamborenea (DT) limited mobility growth model* [4] introduced as a minimal model for ideal molecular beam epitaxy. In particular, we show in Fig. 1 the measured DT exponents in 2+1 dimensions using standard stochastic DT simulations [5,6]. It is clear that the DT exponents ($\alpha \approx 0.6$; $\beta \approx 0.2$; $1/z \approx 0.3$; $\lambda \approx 0.12$) agree very well with those reported in Ref. [1]. Our typical simulated DT growth morphology also agrees remarkably well with the experimental morphology in Ref. [1]. Details on the 2+1 dimensional DT model simulations can be found in the literature [5,6]. The important point we emphasize

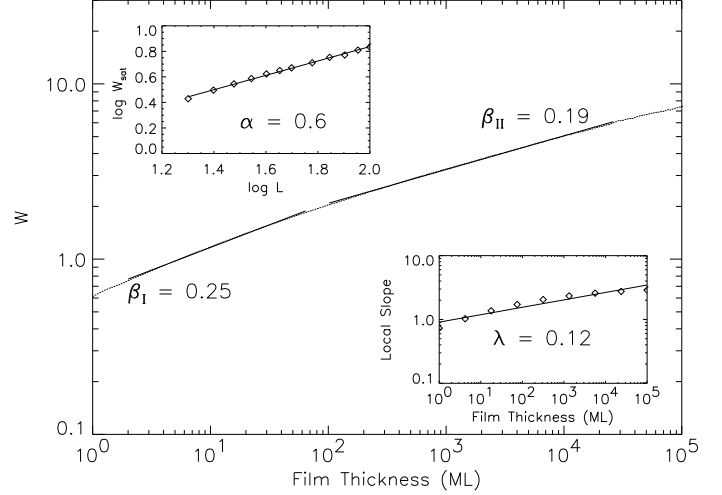


FIG. 1. The interface width as a function of deposition time (average film thickness) in the 500×500 DT model. Top inset: The saturation width W_{sat} vs the substrate size. Lower inset: The local slope vs time.

in this Comment is that DT model produces [6] a mounded growth morphology with a finite local slope exponent ($\lambda \neq 0$) during a very long-lived pre-asymptotic regime (even in the absence of any diffusion bias or Ehrlich-Schwoebel barrier) with its critical exponents (α , β , z) remaining consistent with LD universality precisely as observed in Ref. [1].

We conclude by stating that the fact that the experimental growth reported in Ref. [1] belongs to the DT universality class is *not* surprising because the DT model is a minimal diffusion-driven vapor deposition growth model. It is known [7] that the DT model *asymptotically* belong to the LD continuum universality class although there are very interesting non-asymptotic corrections such as the non-zero slope exponent [6] observed in Ref. [1]. It will be very interesting to experimentally observe some of these non-asymptotic corrections [7] such as anomalous scaling and multifractality in the experimental system of Ref. [1].

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